# 2SD2693A

## Silicon NPN triple diffusion planar type

### For power amplification

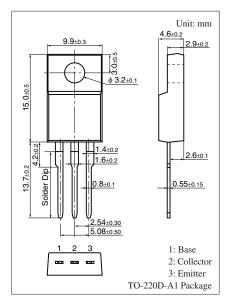
#### Features

- Wide safe oeration area
- $\bullet$  Satisfactory linearity of forward current transfer ratio  $h_{\text{FE}}$
- ullet Low collector-emitter saturation voltage  $V_{CE(sat)}$
- Full-pack package which can be installed to the heat sink with one screw.

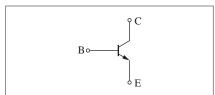
### ■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	80	V	
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	80	V	
Emitter-base voltage (Collector open)	$V_{EBO}$	6	V	
Collector current	$I_C$	3	A	
Peak collector current *	$I_{CP}$	5	A	
Collector power dissipation	P <sub>C</sub>	25	W	
$T_a = 25^{\circ}C$		2.0		
Junction temperature	$T_{j}$	150	°C	
Storage temperature	T <sub>stg</sub>	-55 to +150	°C	

Note) \*: Non-repetitive peak collector current



#### Internal Connection



## ■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open) *1	V <sub>CEO</sub>	$I_C = 30 \text{ mA}, I_B = 0$	80			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = 80 \text{ V}, I_E = 0$			100	μΑ
Collector-emitter cutoff current (Base open)	I <sub>CEO</sub>	$V_{CE} = 80 \text{ V}, I_{B} = 0$			100	μΑ
Emitter-base cutoff current (Collector open)	$I_{EBO}$	$V_{EB} = 6 \text{ V}, I_C = 0$			1	mA
Forward current transfer ratio *1	h <sub>FE1</sub> *2	$V_{CE} = 4 \text{ V}, I_{C} = 1 \text{ A}$	70		250	_
	h <sub>FE2</sub>	$V_{CE} = 4 \text{ V}, I_{C} = 3 \text{ A}$	10			
Collector-emitter saturation voltage *1	V <sub>CE(sat)</sub>	$I_C = 3 \text{ A}, I_B = 0.375 \text{ A}$			0.8	V
Transition frequency	$f_T$	$V_{CE} = 10 \text{ V}, I_{C} = 0.5 \text{ A}, f = 10 \text{ MHz}$		30		MHz
Turn-on time	t <sub>on</sub>	I <sub>C</sub> = 1 A, Resistance loaded		0.1		μs
Storage time	t <sub>stg</sub>	$I_{B1} = 0.1 \text{ A}, I_{B2} = -0.1 \text{ A}$		2.3		μs
Fall time	t <sub>f</sub>	$V_{CC} = 50 \text{ V}$		0.3		μs

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

#### 2. \*1: Pulse measurement

#### \*2: Rank classification

Rank	Q	Р
h <sub>FE1</sub>	70 to 150	120 to 250

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